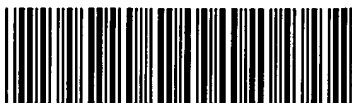


**Search Notes**

Application/Control No.

10/509,631

Examiner

David Mis

Applicant(s)/Patent under  
Reexamination

NAGANO, SEIDO

Art Unit

2817

**SEARCHED**

| Class | Subclass | Date       | Examiner |
|-------|----------|------------|----------|
| 331   | 46       | 12/20/2005 | DM       |
|       | 55       |            |          |
|       | 172      |            |          |
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**INTERFERENCE SEARCHED**

| Class   | Subclass | Date       | Examiner |
|---------|----------|------------|----------|
| USPGPUB | (see     | 12/20/2005 | DM       |
|         | history) |            |          |
|         |          |            |          |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE | EXMR |
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